

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the application of: **Spencer M. Gold, et al.**

Serial No.: **Not Yet Assigned**

Filed: **Herewith**

For: **AN INTEGRATED TEMPERATURE
SENSOR**

Attorney Docket No.: **SMQ-088/P6549**

Group Art Unit:

Examiner:

BOX PATENT APPLICATION

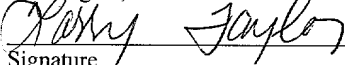
Commissioner for Patents

Washington, D.C. 20231

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Date of Deposit **February 19, 2002**

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Signature

Larry Taylor

Please Print Name of Person Signing

PRELIMINARY AMENDMENT

Dear Sir:

Preliminary to examination of the above-referenced patent application, please amend the application as follows:

In the Specification:

On page 1, line 3 please add the following paragraph with heading:

RECEIVED FEB 20 2002

Reference to Related Applications

The present invention relates to five other applications filed on the same date: A Method and System for Monitoring and Profiling an Integrated Circuit Die Temperature (Atty. Docket: SMQ-087/P6548), A Controller for Monitoring Temperature (Atty. Docket: SMQ-089/P6550), Quantifying a Difference Between Nodal Voltages (Atty. Docket: 03226.116001/P6348), Low Voltage Temperature Independent and Temperature Dependent Voltage Generator (Atty. Docket: 03226.112001/P6322) and Temperature Calibration Using On-Chip Electrical Fuses (Atty. Docket: 03226.108001/P6216).

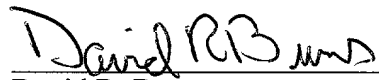
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REMARKS

The above amendment introduces no new subject matter. Entry of the foregoing Preliminary Amendment is in order and requested. If there are any questions regarding the proposed amendment to the application, we invite the Examiner to call Applicants' attorney at the telephone number below.

Respectfully submitted,

LAHIVE & COCKFIELD, LLP



David R. Burns
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Attorney for Applicants

28 State Street
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Date: **February 19, 2002**

10030037-021902

“VERSION WITH MARKINGS TO SHOW CHANGES MADE”

In the Specification:

On page 1, line 3 please add the following paragraph with heading:

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